

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/023,455	OHNISHI ET AL.	OHNISHI ET AL.	
Examiner	Art Unit		
lan M. Ludlow	1743		

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEAR((INCLUDING SE	CH NOT)
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updated search		4/17/2006	JML